



FRIEDRICH-SCHILLER-  
UNIVERSITÄT  
JENA



Physikalisch-Technische Bundesanstalt  
Nationales Metrologieinstitut

# NANO-FAME

*Micro and Nano **fabrication** technology meets Nano **metrology***

07.10.2022 Uni Jena

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The meeting will take place following the "Photonics Days Jena" on 5 and 6 . October 2022.

09:00 Introduction (Thomas Siefke and Uwe Zeitner)

**09:15 Fundamentals of Nanofabrication (Thomas Siefke)**

09:45 Surface Nano structuring via Ion Irradiation (Johannes Kaufmann)

10:05 Optical properties of black silicon structures ALD-coated with Al<sub>2</sub>O<sub>3</sub> (David Schmelz)

10:25 Coffee Break

10:50 Switchable optics based on guided mode resonance in lithographically patterned vanadium dioxide (Markus Walther)

11:10 Presentation V (tba)

11:30 Lunch

**12:30 Fundamentals of X-ray/EUV Nano metrology (Victor Soltwisch)**

13:00 Optical constants in the EUV and soft X-ray spectral range (Qais Saadeh)

13:20 GIXRF and GEXRF for dimensional and analytical nanometrology (Philipp Hönicke)

13:40 Coffee Break

14:00 From grazing incidence X-ray to near normal EUV scattering (Leonhard Lohr)

14:20 Imaging Molecular Orbitals on Sub-Nano Scales with Photoemission Orbital Tomography (Hans Kirschner)

14:40 Coffee Break

15:00 Tour (RR, optics lab, Uni Jena)

16:00 Tour (OptiXfab)

17:00 Get-together



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